

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.	10/539,247	Conf. No.	9258
In Re Application of:	Gattiker <i>et al.</i>	Art Unit:	2829
Filed:	06/16/2005	Dkt. #:	BUR920020068US1 (IBMF-0010-US)
Cust. No.:	45094	Examiner:	Nguyen, Vinh P.

Title: **INTEGRATED CIRCUIT TESTING METHODS USING WELL BIAS
MODIFICATION**

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTAL AMENDMENT

Sir:

I. INTRODUCTORY COMMENTS

Please reconsider the above-identified application in light of the following amendments and remarks.

The Claims are reflected in the listing of claims that begin on page 2 of this paper.

Remarks begin on page 9 of this paper.